

**Notice of References Cited**

Application/Control No.

09/935,344

Applicant(s)/Patent Under  
Reexamination  
JIRA ET AL.

Examiner

Zachariah Lucas

Art Unit

1648

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,544,528	04-2003	Yamamoto, Janet K.	424/208.1
*	B	US-4,568,542	02-1986	Kronenberg, Lee H.	424/209.1
*	C	US-6,383,806	05-2002	Rios, Adan	435/339.1
*	D	US-6,024,953	02-2000	Lathe et al.	424/93.2
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 57175127 A	10-1982	Japan	YOSHIZAWA et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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